

# RADIATION TEST SUMMARY

PART TYPE: 2N7236

**DESCRIPTION: P-CHANNEL MOSFET** 

REPORT NO.: RD 209

PARAMETERS PLOTTED:

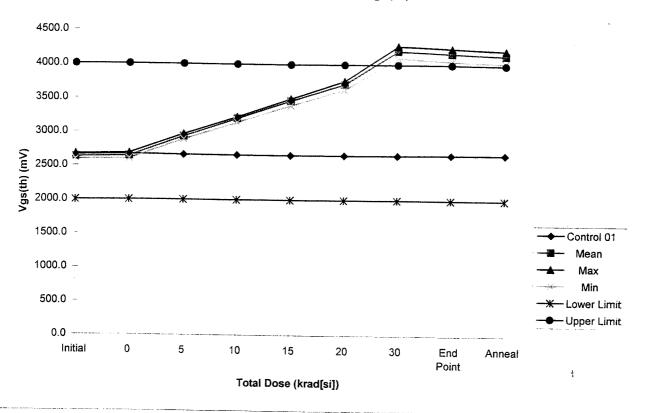
VGS(th)

NOTE:

The results for the remaining parameters showed no significant change and hence plots were not considered necessary.



## Radiation Results for Vgs(th)



Dose (kRad)	Control 01	Mean	Max	Min	Lower Limit	Upper Limit	Std.Dev.
	(mV)	(mV)	(mV)	(mV)	(mV)	(mV)	Old.Bev.
Initial	2662.6	2630.6	2673.7	2595.3	2000	4000	32.73
0	2668.6	2639.6	2684.1	2601.2	2000	4000	34.88
5	2660.2	2929.7	2964.0	2886.3	2000	4000	32.71
10	2660.1	3199.6	3222.9	3141.7	2000	4000	38.77
15	2657.7	3466.7	3497.9	3397.1	2000	4000	47.62
20	2659.4	3712.4	3758.3	3630.9	2000	4000	58.02
30	2656.5	4204.4	4277.7	4097.3	2000	4000	81.16
End Point	2666.4	4169.0	4243.3	4055.6	2000	4000	84.69.
Anneal	2672.4	4144.3	4217.8	4030.6	2000	4000	85.92

Lot size for statistics : 4 devices

RD 209 Date code 9616

Rev. MA IRRADIATION TEST PLAN NO. Issue No. 1 Date: OCTOBER 1995 Date: NAENVISAT-1 Page: 1/4 PO-PL-IGG-PL-0027 RD209 RIR 73542 Component Designation:TRANSISTOR, Irradiation Spec No. NA Component No. MOSFET, P-CHANNEL, POWER TYPE **JANS2N7236** 3 2N7236 lss. Rev. 5 Electrical Project/Programme Specifications Acceptance Measurements Evaluation Generic MIL-S-19500 Iss. J Element **ENVISAT-1** Iss. A Diffusion In-situ Detail MIL-S-19500/595 Remote Lot 9 Originator: IGG CT Manufacturer: Name: Int. Rectifier Test Facility: Name: ERA Address: LEATHERHEAD, SURREY Name: S THACKER Address: Hurst Green, Oxted **ENGLAND** Surrey, England 11 12 10 **Radiation Source** Sample Size: **Annealing Test** Radiation Level: **Exposure** Single **COBALT 60** Control Device: 1 Multiple YES X NO See Below 13 (Each Test) 17 Single Exposure Multiple Exposure: Dose [Krad(Si)] Irradiation Steps In accordance with the applicable Dose Rate [rad(Si)/s] Appendix to this Plan for each **Exposure Time** Dose [Krad(Si)] test. Dose Rate [rad(Si)/s] 18 Not applicable Exposure Time(s) 19 Bias Requirements: During and after Exposure (for remote Electrical Measurements): YES **Bias Conditions:** Test Circuits: The Electrical Bias circuit is given in Figure 1 in the applicable Appendix to this Plan. Shielding is required to minimize dose enhancement effects caused by low energy, scattered Shielding: radiation. The test units shall be enclosed in a Pb/Al container of Pb 1.5mm minimum, surrounding on inner shield of 0.7 to 1.0mm Al. Irradiation Test Sequence(applied for each radiation test per the applicable Appendix to this plan). 21 Test Step Description Requirements 1 Irradiation Test Samples Quantity 5 devices shall be selected from the lot delivered to IGG. Selection 2 Serialisation Serialisation - (if the devices are not already serialised) Test units shall be serialised 1 to 4 and the control unit shall be 5. 3 **Initial Electrical Measurements** Per Table A herein - (Read-and-Record) - on all 5 parts at IGG. (See (at IGG) Remarks 1 and 2). 4 Initial Electrical Measurements Per Table A herein - (Read-and-Record) - on all 5 parts at ERA. (See (at ERA) Remarks 1 and 2). Set-up of Test 5 Verify Bias Circuit and Voltages (In-situ) for 4 test units.

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Irradiation Test Sequence (Cont.)

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2

madiation	rest Sequence (Cont.)	
Test Step	Description	Requirements
6	Irradiation Exposure	Verify radiation dose rate and position in the chamber to achieve required dose. Verify and witness duration of exposure to achieve required dose.
7	Intermediate Electrical Measurement (at ERA)	Bias to be maintained until test is performed. Test per Table A herein - (Read-and-Record) - on all 5 parts. Test to be performed immediately upon removal from chamber (less than 10 mins interval). Upon completion of test 4 test units shall be replaced in bias circuit and returned to chamber. Maximum interval between two consecutive exposures to be 30 mins. (See Remark 2).
8 to 7 + 3n	Repeat Set-up/Exposure/Test sequence upto a Final Total Dose as per the applicable Appendix	Repeat Steps 5, 6, 7 for a total of n cycles (see applicable Appendix). (See Remark 3)
8 + 3n	End Point Electrical Measurements (at IGG)	Per Table A herein - (Read-and-Record) - on all 5 parts at IGG. (See Remarks 2 and 4).
9 + 3n	Annealing	Bias shall be maintained during Annealing for 4 test units. Annealing shall be at room temperature for 168 hours.
10 + 3n	Final Electrical Measurements (at IGG)	Per Table A herein - (Read-and-Record) - on all 5 parts at IGG (See Remark 2).
11 + 3n	Total Dose Irradiation Test Report	ESA/SCC No. 22900

Remarks

- The initial electrical measurements performed at IGG (Test Step 3) shall be performed within 24 hours of the 1. initial electrical measurements at ERA (Test Step 4).
- 2. All electrical testing shall be performed on the same set of equipment in order to achieve correlation of results both at IGG and ERA. All results plus details of any failuges shall be advised to Project.
- The set-up/exposure/test sequence shall be stopped for any device that exhibits repeated functional failure. 3.
- The End Point electrical measurements (Test Step 8 + 3n) performed at IGG shall be performed within 24 4. hours of the last electrical measurement at ERA (Test Step 7 + 3n).

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NA Date: NA

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TABLE A - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE -  $T_{amb}$  = +25  $\pm 5\,^{\circ}$ C BEFORE, AT INTERMEDIATE POINTS, AND ON COMPLETION OF IRRADIATION.

NO.	CHARACTERISTICS	SYMBOL	MIL-STD-750	TEST	LIN	IITS	UNIT
			TEST METHOD	CONDITIONS	MIN.	MAX.	
1	Breakdown Voltage Drain to Source	BV <sub>DSS</sub>	3407 Bias Cond. C	$l_D = -1.0 \text{mAdc}$ $V_{GS} = 0$	-100	-	Vdc
2	Gate Threshold Voltage	V <sub>GS(th)</sub>	3403	$V_{DS} = V_{GS}$ $I_D = -0.25 \text{mAdc}$	-2.0	-4.0	Vdc
3	Gate Current	l <sub>oss</sub>	3411 Bias Cond. C	$V_{GS} = -20Vdc$ $V_{DS} = 0$	-	-100	nAdc
4	Drain Current	I <sub>DSS</sub>	3413 Bias Cond C	$V_{DS} = -80Vdc$ $V_{GS} = 0$	<b>-</b> ,	25	μAdc
5	Drain Source ON Resistance 1	r <sub>ds(ON)1</sub>	3421	$V_{GS} = -10Vdc$ $I_D = -11Adc$ (Notes 2 and 3)	-	0.20	Ω
6	Drain Source ON Resistance 2	F <sub>DS(ON)2</sub>	3421	$V_{GS} = -10Vdc$ $I_{D} = -18Adc$ (Notes 2 and 3)	-	0.22	Ω

#### **NOTES**

1. The limits specified in this Table only apply to the first intermediate electrical measurements at dose 5Krad(Si). For all other intermediate, end point and final electrical measurements, these limits shall not apply but the tests shall be performed and the result recorded for information and characterisation purposes.

Parametric failures to the limits given in this Table could possibly occur at any irradiation level greater than 5Krad(Si).

- 2. Pulsed: Pulse Width  $\leq$  300uS, Duty Cycle  $\leq$ 2%.
- 3. Measured within 2mm of case.

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NA Date:

APPENDIX:

COMPONENT TYPE:

2N7236

This appendix defines the specific radiation test requirements applicable to the following ENVISAT-1 user(s):-

USER CODE	USER COMMENT	
MWCESC	Ref. N/A	

The following specific requirements shall apply:-

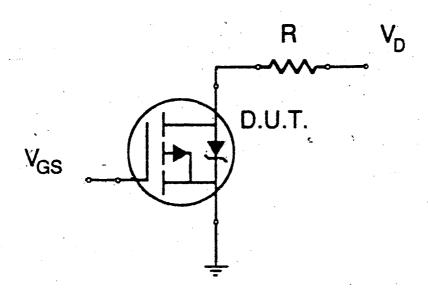
### MULTIPLE EXPOSURE/IRRADIATION STEPS:

a) WOLTIFEE EXTOGORIZATION	31E1 0.		· · · · · · · · · · · · · · · · · · ·		
Irradiation Steps (n)	1	2	3	4 ·	5
Dose [Krad(Si)]	5	5	5	5	10
Accumulated Dose[Krad(Si)]	5	10	15	20	30
Dose Rate [rad(Si)/s] (See note)	3	3	3	· з	3
Exposure Time(s) (See note)	1667	1667	1667	1667	+667
					· ·

3333

Note: The dose rates and exposure times given are nominal conditions and may be adjusted during irradiation testing to achieve convenient test points. The actual dose rate shall not exceed 3rad(Si)/s. The dose rates and exposure times used during the testing shall be recorded for each test step.

#### b) **ELECTRICAL BIAS CIRCUIT FOR IRRADIATION TESTING:-**



NOTES: i) Bias conditions  $V_{GS} = -10Vdc$ ,  $V_{D} = -30Vdc$ 

> $R = 300\Omega \pm 1\%$  to give  $I_D = -100$ mAdc ii)

QA/4/02/010 Issue 1

Lot number : RD209 Order number : D/C 9618

Vendor : IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,9.

: INITIAL EMS @ 166

: 2N7238 PO-PL-IGG-0027 ISS 1 / V1.0 15/8/96 PAR

Test	steps
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1V(BR)DSS 2V6S		100.0 2000.0	7 9 2 7 7 7	700.0 4000.0	V mV
J. −IGSS ⟨FWD⟩	(	0.0	),,,	100.0	nΑ
4IGSS (REV)	, ,	0.0	),,,,	100.0	nΑ
SIDSS	(	0.0	)	25.0	uA
6. RDS οπ.	<b>〈</b>	0.000	} , , ,	0.200	Ohm
7. RDS on	(	0.000	)	0.220	Ohm

	1		3		5		2 7		9		
1.1 C V1	123.6	į	124,2	1	124.4	!	124.0		125.1		The state of the s
2.1 [mV]	2662.6	;	2595.3	ļ	2673.7	1	2520.4	į	2832.9	<u>!</u> }	
3.1 [nA]	1.5	;	1.2	į	1.2	!	1.8	i	1.3	i	
4.1 [nA]					1 . 1					į	
5.1 [uA]	Ø . Ø	}	0.0	{	0.0	i	Ø.Ø	i	Ø. Ø	1	
6.1 [Ohm]	0.123	1	0,123	}	0.124	ì	0.128	1	0.129	!	-
7.1 [Ohm]	0.125	İ	0.125	ì	0.125	į	0.130	i	0.131	1	

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OF FESTSYSTEME Statistics 03 Vers. 2.15 for TA07F RD209\_2N7236\_INJT\_EMS\_@\_ERA /\_U1,0 15/8/96 PAR

Results file : RD209\_2N7236\_INIT\_EMS\_0\_ERA from: 30.10.86 / 08:31:22

Operator : PAUL RUSSELL

Part number Lot number

: 2N7236 : RD209

Order number : D/C 9618 Vendor

: IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,9.

: INITIAL EMS @ ERA

: 2N7236 PO-PL-18G-PL-0027 ISS 1 / V1.0 15/8/96 PAR

Test steps

1V(8R)DSS		100.0		700.0	( <i>)</i>
2VGS		2000.0	2 2 2	4000.0	mV
JIGSS (FWD)	ξ.	0.0	) }	100.0	nA.
4I6SS (REV)	<	$\emptyset : \emptyset$	)	100.0	nΑ
5IDSS	<	0 3		25.0	uА
6. RDS on	<	0.000	)	0.200	Ohm
7. RDS on	(	0.000	>	0.220	Ohm .

	Ţ,		J		S		7.		3		
1.1 E V]	123,3		123.9		124.0		123.8		124.9		a material more artis, material from those same such
2.1 [mV]	2668.6	}	2601.2	}	2684.1	;	2627.1	į	2645.8	1	
3.1 [nA]	1.3	;	1.3	į	1.3	-	1.3	į į	1.3	1	-
4.1 [nA]	1.2	į	1.2	j	1.2	ì	1.2	j	1.2	}	
S.1 [wA]	Ø . Ø	į	0.0	į	0.0	1	3.0	!	0.0	[	
6.1 [Ohm]	0.121	j	0.120	;	0.120	}	0.125	1	0.125	i	
7.1 [Ohm]	0.122	{	3,122	į	Ø.123.	į.	0.127	4	0.128	i	

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92-TESTSYSTÉMÉ Statistics 03 Vens. 2.16 for TA07F RD209\_2N7236\_EMS\_0\_5\_KRAD / V1.0 15/8/96 PAR

Part number

: 2N7236

Lot number

: RD209

Onder number : D/C 9616

Vendor

: IR

: CONTROL S/No 01 : RAD SAMPLE S/NoS 3,5,7,9

: EMS @ 5 KRAS

: 2N7238 P0-PL-IGG-PL-0027 ISS 1 / V1.0 15/8/96 PAR

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1V(BR)DSS 2V6S			2 8 2	700.0 4000.0	w.V
3, -1699 (FWD)	(	0.0	>	100.0	กล
4IGSS (REV)	<	0.0	)	100.0	nΑ
S. HIDSS	{	0.0	<b>)</b>	25.0	uA
6, RDS on	<	0.000	),,,	0.200	Ohm
7. RBS on	(	9.000	>,,,,	0.220	Ohm

	1.		3		S		7		Ţ,		
1.7 E V1	123.5	{	123.2	. <u></u> !	123.8	1	123.4		124.7.		and the sale the title sale and the
2,1 [mV]	2660.2	į	2886.3	ŧ	2964.0	3	2926.7	•	2941,6	į	
J.1 [nA]	1.4	į	1.4	į	1.4	[	1.3	į	1.4	!	-
4.1 [nA]	1.3	į	1.3	.}	1.3	1	1.3	į	1.3	}	
5.1 (uA)	3.3	{ 1	0.0	į	0.0	1	Ø.1	į	Ø.:	1	
6.1 [Ohm]	0.123	ļ	0.117	į	0.120	į	0.125	ļ	0.126	1	
7.1 [Ohm]	0.125	;	0.113	{	0.122	į	0.128	!	0.129		

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SZ-TESTSYSTÉME Statistics 03 Vers. 2.15 for TA07F RD209\_2N7236\_EMS\_@\_10\_KRAD / V1.0 15/8/96 PAR

Results file : RD209\_2N7236\_EMS\_0\_10\_KRAD from: 30.10.96 / 10:07:35

Operator : PAUL RUSSELL

Part number Lot number

: 2N7236 : RD209

Order number : D/C 9616

Vendor

: IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,9

: EMS @ 10 KRAD

: 2N7236 P0-PL-IGG-PL-0027 ISS 1 / V1.0 15/8/96 PAR

Test steps

1V(BR)098 2V68				700.0 4000.0	V mV
31099 (FWD)	(		>		Aп
4IGSS (REV)	<	00	) , , ,	100.0	nA
5IDSS	(	0,0	} = = =	25.0	uА
6. RDS on	<	0.000	)	0.200	Ohm
7. RDS on	(	0.000	>	0.220	Ohm

	Ţ.		3		5		7		3		
1.1 E V] 2.1 EmV]	· · · · · · · · · · · · · · · · · · ·								124.9 3219.5		AND SEED STOLE STOLE SEED COME CALLEY CALLEY CALLEY
3.1 [nA]	1.4	ĺ	1.4	í	1.5	į	1.5	!	1.5	í	-
5.1 EuAl	9.8	į	0.3	į	0.2	į	0.S	ļ	0.5		
6.1 [Ohm] 7.1 [Ohm]	0.124 0.126		Ø.119 Ø.121								

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SZ-TESTSYSTEME Statistics 03 Vens. 2.15 for TA07F RD209\_2N7236\_EMS\_@\_15\_KRAD / V1.0 15/8/96 PAR

Results file : RD209\_2N7236\_EMS\_@\_15\_KRAD from: 30.10.96 / 10:39:57

Operator : PAUL RUSSELL

Part number

: 2N7236

Lat number

: RD209

Order number : B/C 9616

Vendor

: IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,9.

: EMS @ 15 KRAD

: 2N7236 PO-PL-IGG-PL-0027 ISS 1 / V1.0 15/8/96 PAR

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		7.	- 5			

1V(8R)DSS		100.0	- ¢ -	700.0	V
2VGS	2	000.0	2 2 1	4000.0	ΜV
31888 (FWD)	(	0.0	)	100.0	πA
4IGSS (REV)	4	0.0	),,,	100.0	nΑ
5IDSS	(	0.0	>	25.0	uА
6. RDS on	<	0.000	)	0.200	Ohm
7. RDS on .	(	0.000	<pre>&gt;</pre>	0.220	ಿಗ್ಗ

	ţ.		3		5		7		3		4
1.1 ( V)	123.9	ĺ	123.3		124.0	:	123.7	!	125.0	1	20 100 100 100 100 100 100 100 100 100 1
2.1 [mV]	2657.7	ļ	3397.1	į	3474.5	į	3497.1	}	3497.9	į	
3.1 [nA]	1.6	į	1.5	(	1.6	í	1.5	í	1.8	1	-
4.1 [nA]	1,5	ŀ	1.5	)	1.5	;	1.5	1	1.5	}	
5.1 (wA)	3.0	í Š	0.7	Í	0.5	ì	1.2	ļ	1 1	ř	
8.1 [Ohm]	0.126	}	0.120	}	0.125	į	0.130	į	0.131	3 3	
7.1 (Ohm 1	0.128	1	0.123	ţ	0.127	f	0.134	į	0.135	(	

07 TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F RD208\_2N7236\_FMS\_0\_20\_KRAD / V110 15/8/86 PAR

Part number Lot number

: 2N7236 : 80209

Order number

: D/O 9616

Vendor

: IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,9.

: EMS @ 20 KRAD

: 2N7236 PO-PL-IGG-PL-0027 ISS 1 / V1.0 15/8/96 PAR

Teat ateps

1V(8R)055		100.0	700.0	Ų
2V6S	2	000,8	4000.0	mŲ
31098 (FWD)	(	Ø.Ø >	100.0	nΑ
4, -IGSS (REV)	<b>〈</b>	Ø.Ø )	100.0	nΑ
S, -IDSS	4	Ø.Ø. )	25.0	ųΑ
6. RDS on	₹	0.000 ),	0.200	Ohm
7. RDS on	4	0.000 >	0.220	Ohm

	τ.	3	5	7	9	
1,1 ( (/)				123.7		
2.1 [mV] 3.1 [mA]		1.5	1.5	1 3758.3	1.5	-
4.1 [nA] 5.1 [uA]	1 , 4			1 1.5		
6.1 [Ohm] 7.1 [Ohm]	0.124   0.126					·

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F RD209\_2N7236\_EMS\_@\_30\_KRAD / V1.0 15/8/96 PAR

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Part number Lot number

: 2N7236 : RD209 Onder number : D/C 9616

Vendor :

: IR

: CONTROL S/No Ø1 ; RAD SAMPLE S/NoS 3,5,7,9

: EMS @ 30 KRAD

: 2N7236 PO-PL-IGG-PL-0027 ISS 1 / V1.0 15/8/96 PAR

Test steps

1V(BR)DSS 2V6S 3IGSS (FWD) 4IGSS (REV)	(			700.0 4000.0 100.0 100.0	V MV nA nA	
SIDSS	(	0.0	·	25.0	Più:	
G. RDS on	<	0.000	)	0.200	Ohn	
7. RDS on	€	0.000	> = =	0.220	Ohm	

•	Ĭ.		3		5		7		3		
1.1 & V3	123.8	!	123.3		124.1	1	123.6	1	125.0		
2 = 1 [mV]	2656.5	ì	4097,3	7 }	4186.8	FI	4277.7	F	4255.5	F)	
3.1 (nA)	1.7	İ	1.5	1	1.8	i	1.6	í	1.6	1	-
4.1 [nA]	1.6	}	1.4	1	1.5	}	1.5	į	1.5	j	
5.1 EuA1	0.0	ŧ	1.8	1	1.5	1	2.3	į	2.2	í	
5.1 [Ohm]	0.125	1	0.125	)	0.129	;	0.130	,	0.137	)	
7.1 (Ohm 1	0.127	į	0.128	ţ	0.133	1	0,146	1	0.142		

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SZ-TESTSYSTEME Statistics 03 Vers. 2,15 for TA07F RD209\_2N723E\_END\_POINT\_EMS / V1.0 15/8/96 PAR

Operator : PAUL RUSSELL Part number : 2N7236

Lot number

: RD209 Order number : D/C 9616

Vendor

: IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,9

: END POINT EMS

: 2N7238 PO-PL-16G-PL-0027 ISS 1 / V1.0 15/8/96 PAR

Test steps

1V(8R)DSS 2V6S	2	100.0 2000.0	700.0 4000.0	V mV
3IGSS (FWD)	(	∅.∅ >	100.0	πA
4, -IGSS (REV)	<u> </u>	0.0 ),,,	100.0	nΑ
51038	(	Ø.Ø >	25.0	uА
6. RDS on	<<	0.000)	0.200	0hm
7. RDS on	(	0.000 )	0.220	Ohm

	ļ.	 3.		5		7.		9		
1.1 [ V]		124.0								
2.1 [mV] 3.1 [nA]		4055.6 0.J								ъ.
4.1 [mA] 5.1 [uA]	0.2 0.0					0.3 2.2				
6.1 [Ohm] 7.1 [Ohm]	0,122 0.124		į	0.131	)	Ø.136 Ø.141	}	Ø.138 Ø.143	) ]	

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F RD209\_2N7236\_POST\_ANNEAL\_EMS / V1.0 15/8/86 PAR

Results file : 'RD209\_2N7236\_POST\_ANNEAL\_EMS from: 08.11.96 / 14:24:04

Part number

Operator : PAUL RUSSELL

Lot number

: 2N7236 : RD209 Order number : D/C 9616

Vendor

: IR

: CONTROL S/No 01 ; RAD SAMPLE S/NoS 3,5,7,8

: POST ANNEAL EMS

: 2N7236 PO-PL-IGG-PL-0027 ISS 1 / V1,0 15/8/96 PAR

Test steps

1V(BR)DSS 2VGS 3IGSS (FWD) 4IGSS (REV) 5IDSS 6. RDS on	2000.0 ( 0.0 ( 0.0 ( 0.0 ( 0.000	) ) )	4000.0 100.0 100.0 25.0 0.200	V mV nA nA uA Ohm
7. RDS on	⟨ ∅.000	) )	0.220	Ohm

	1		3		5		i seng		9		
1.1 [ V] 2.1 [mV]			123.9 4030.5								* man man man man man man man man man man
3.1 [nA] 4.1 [nA]	1.8	i		į	1.5	1	1.6	i	1.6	!	
5.1 [uA] 6.1 [Ohm]	Ø.0 Ø.121	!	2.1	1	1.8	į	2.2	į	2.0	į	÷
7.1 [Ohm]	0.123		0.130 0.133	•	0.13 0.13		0.137 0.142	•	0.10		